

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit	Page 1 of 1	
Tan Dean D. Nguyen		3629		

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*	B	US-2002/0059264	05-2002	Fleming et al.	707/100
*	C	US-2002/0173997	11-2002	Menard et al.	705/7
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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